

Application/Control	No.
10/750.872	

Reexamination LEE ET AL.

Applicant(s)/Patent under

Art Unit 3744

Examiner Chen-Wen Jiang

_				ISSUE	CL	.AS	SIF	ICAT	ION			
			INTERNATIONAL CLASSIFICATION									
CLASS SUBCLASS							CI	LAIMED	NON-CLAIMED			
	62		507			25	В	39	/04		1	
CROSS REFERENCES						25	D	19	/00		,	
CLASS	SUBCLA	SS (ONE S	UBCLASS PE	ER BLOCK)	F	23	ו	19	700		<b>'</b>	
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(Legal Instruments Examiner) (Date)

(Primary Examiner)

(Date)

**Total Claims Allowed: 17** 

O.G. Print Claim(s)

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O.G. Print Fig.

	laims											□СРА			□ T.D.			☐ R.1.47	
Final	Original		Final	Original .		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
1	1			31			61			91			121			151			181
2	2	ŀ		32			62			92	-		122			152			182
	3			33			63			93			123			153			183
3	4			34			64			94			124			154			184
4	5			35			65	]		95			125			155			185
10	6			36			66	]		96			126			156			186
11	7			37			67	]		97			127			157			187
12	8			38			68	]		98			128			158			188
5	9			39			69	]		99			129			159			189
6	10			40			70			100			130			160			190
7	11_			41			71			101			131			161			191
8	12			42			72			102			132			162			192
9	13			43			73	]		103			133			163			193
13	14			44			74	]		104			134			164			194
14	15			45			75			105			135			165			195
_15	16			46			76			106			136			166			196
16	17			47			77			107			137			167			197
17	18			48			78			108			138			168			198
	19			49			79	]		109			139			169			199
	20			50			80			110			140			170			200
	21			51			81			111			141			171			201
	22			52			82			112			142			172			202
	23_			53			83			113			143			173			203
į	24			54			84			114			144			174			204
	25			55			85	]		115			145			175			205
	26			56			86			116			146			176			206
	27			57			87			117			147			177			207
	28			58			88			118			148			178			208
	29			59			89	]		119			149			179			209
L	30			60			90	L		120			150			180			210